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Understanding Embedded - FPGAs (Field Programmable Gate Array)

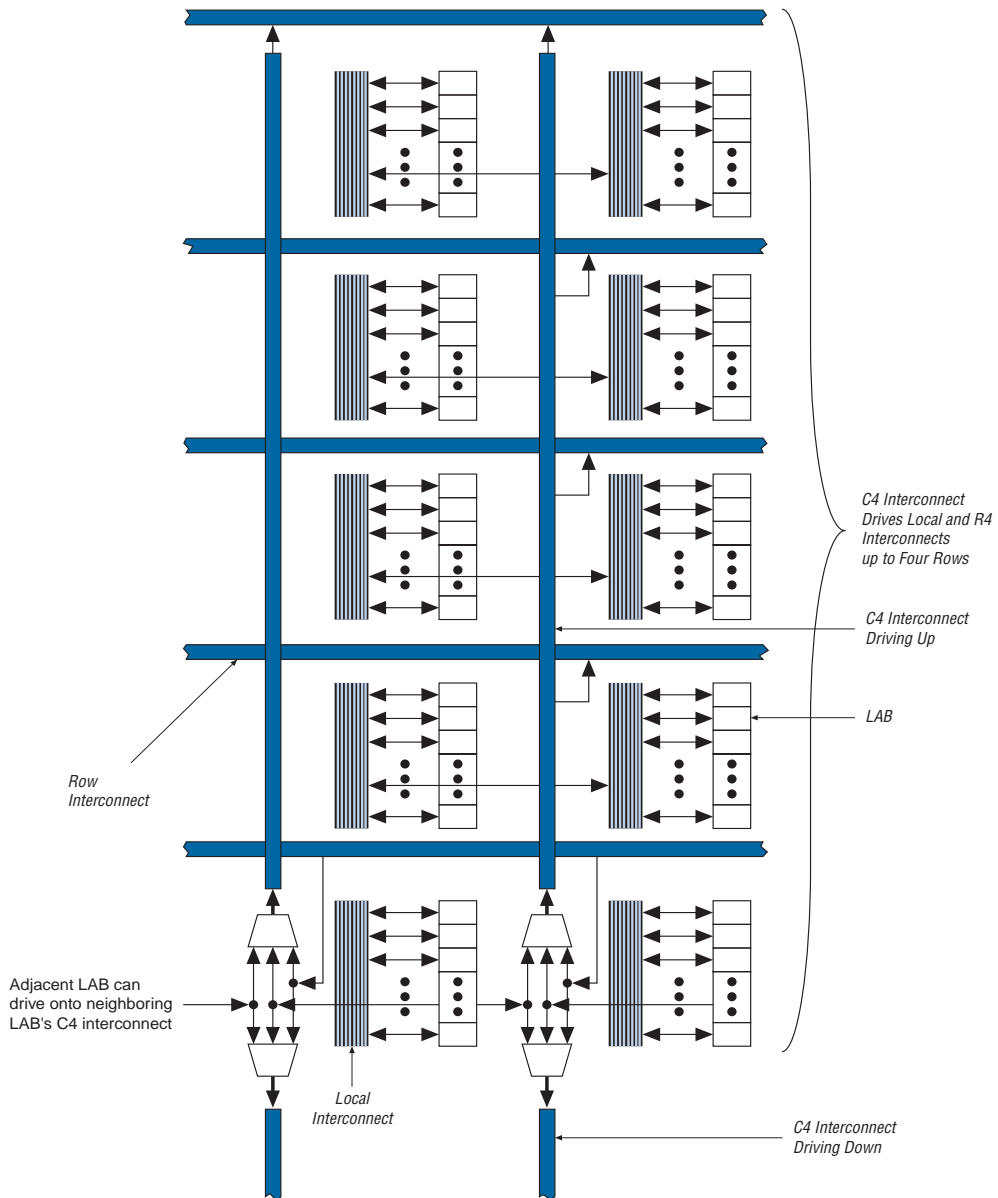
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1846
Number of Logic Elements/Cells	18460
Total RAM Bits	1669248
Number of I/O	586
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA, FCBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s20f780c7n

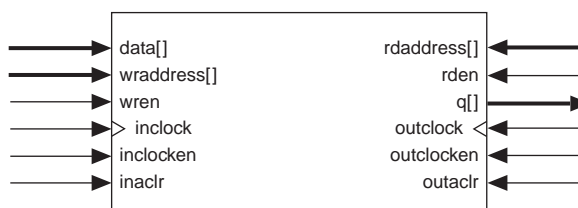
Figure 2–11. C4 Interconnect Connections *Note (1)***Note to Figure 2–11:**

(1) Each C4 interconnect can drive either up or down four rows.

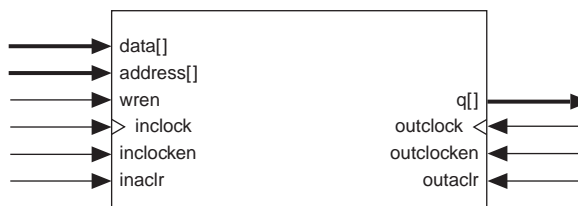
In addition to true dual-port memory, the memory blocks support simple dual-port and single-port RAM. Simple dual-port memory supports a simultaneous read and write and can either read old data before the write occurs or just read the don't care bits. Single-port memory supports non-simultaneous reads and writes, but the `q[]` port will output the data once it has been written to the memory (if the outputs are not registered) or after the next rising edge of the clock (if the outputs are registered). For more information, see [Chapter 2, TriMatrix Embedded Memory Blocks in Stratix & Stratix GX Devices](#) of the *Stratix Device Handbook, Volume 2*. [Figure 2–13](#) shows these different RAM memory port configurations for TriMatrix memory.

Figure 2–13. Simple Dual-Port & Single-Port Memory Configurations

Simple Dual-Port Memory



Single-Port Memory (1)



Note to Figure 2–13:

- (1) Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The memory blocks also enable mixed-width data ports for reading and writing to the RAM ports in dual-port RAM configuration. For example, the memory block can be written in $\times 1$ mode at port A and read out in $\times 16$ mode from port B.

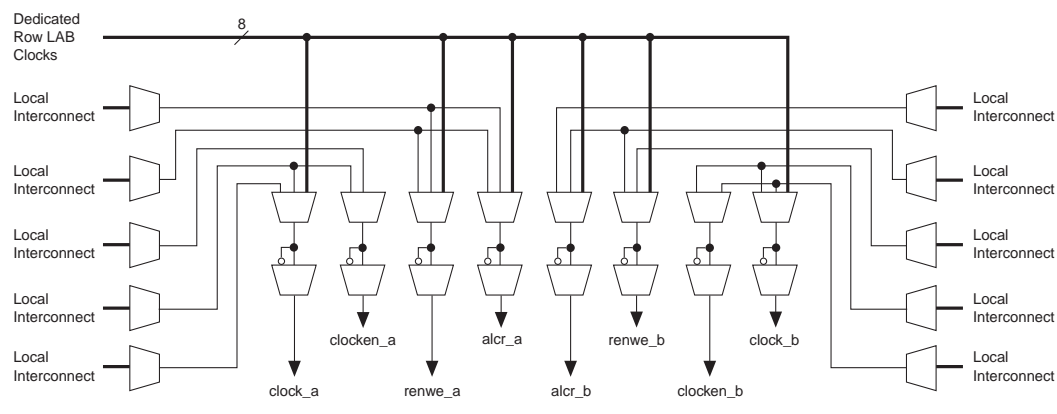
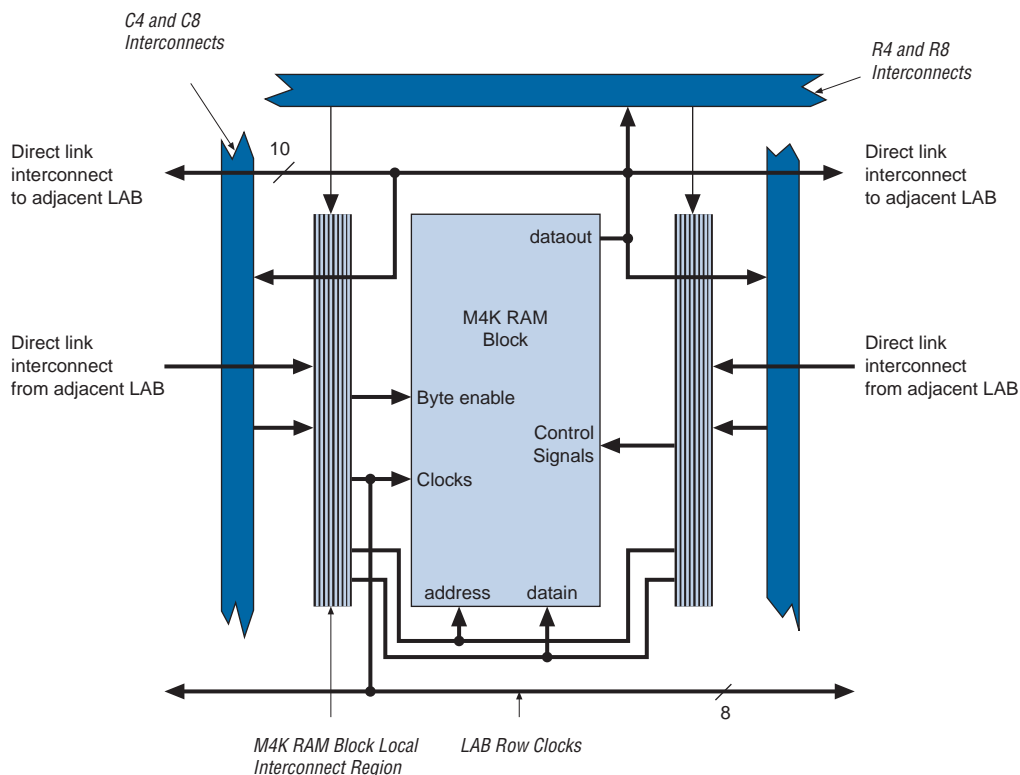
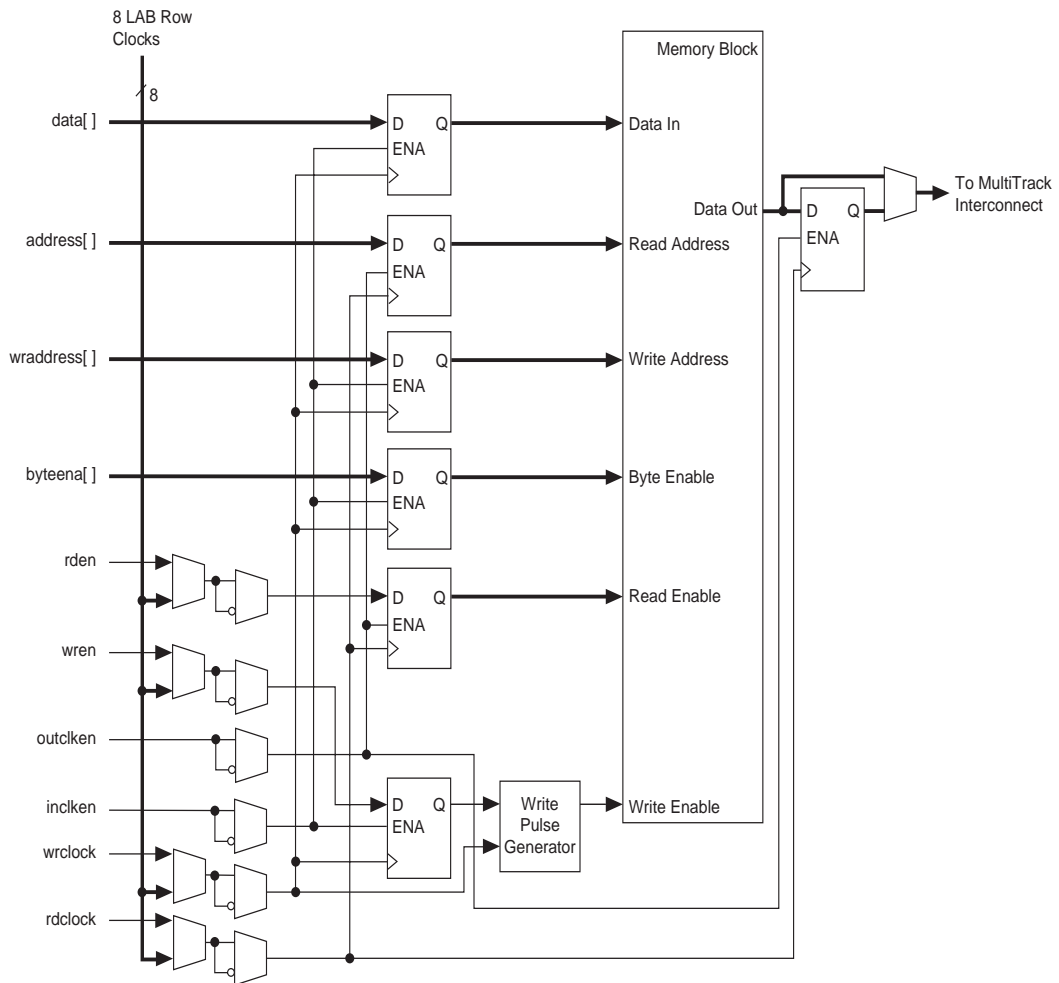
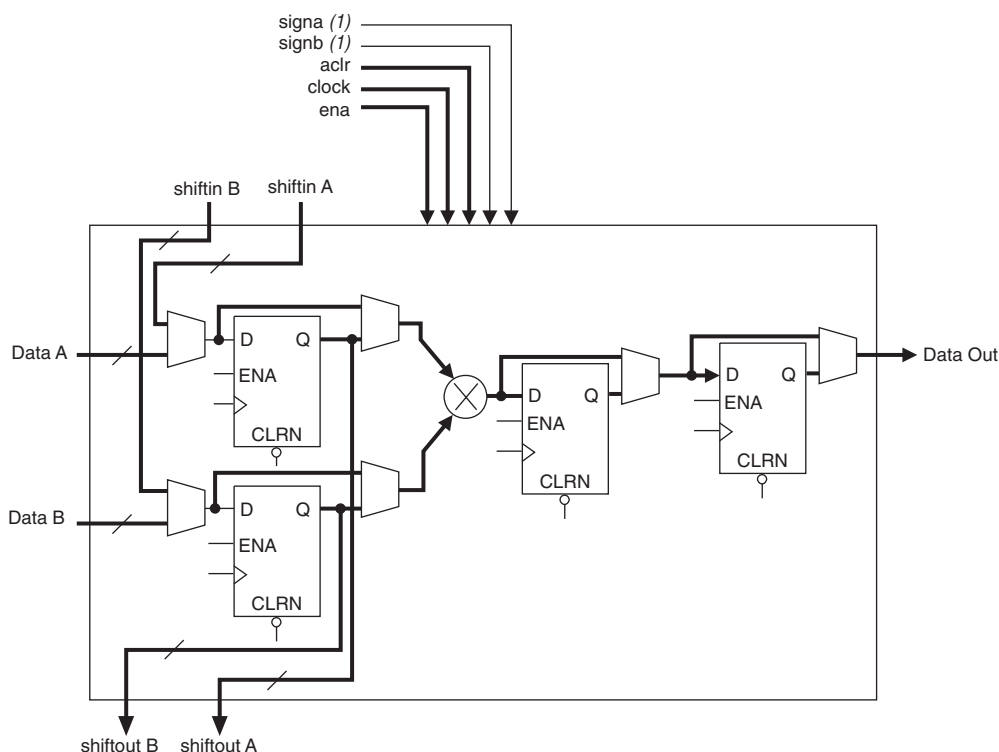
Figure 2–17. M4K RAM Block Control Signals**Figure 2–18. M4K RAM Block LAB Row Interface**

Figure 2–27. Read/Write Clock Mode in Simple Dual-Port Mode *Notes (1), (2)***Notes to Figure 2–27:**

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Figure 2–35. Simple Multiplier Mode**Note to Figure 2–35:**

- (1) These signals are not registered or registered once to match the data path pipeline.

DSP blocks can also implement one 36×36 -bit multiplier in multiplier mode. DSP blocks use four 18×18 -bit multipliers combined with dedicated adder and internal shift circuitry to achieve 36-bit multiplication. The input shift register feature is not available for the 36×36 -bit multiplier. In 36×36 -bit mode, the device can use the register that is normally a multiplier-result-output register as a pipeline stage for the 36×36 -bit multiplier. Figure 2–36 shows the 36×36 -bit multiply mode.

and/or output enable registers. A programmable delay exists to increase the t_{zx} delay to the output pin, which is required for ZBT interfaces.

Table 2–24 shows the programmable delays for Stratix devices.

Table 2–24. Stratix Programmable Delay Chain	
Programmable Delays	Quartus II Logic Option
Input pin to logic array delay	Decrease input delay to internal cells
Input pin to input register delay	Decrease input delay to input register
Output pin delay	Increase delay to output pin
Output enable register t_{CO} delay	Increase delay to output enable pin
Output t_{zx} delay	Increase t_{zx} delay to output pin
Output clock enable delay	Increase output clock enable delay
Input clock enable delay	Increase input clock enable delay
Logic array to output register delay	Decrease input delay to output register
Output enable clock enable delay	Increase output enable clock enable delay

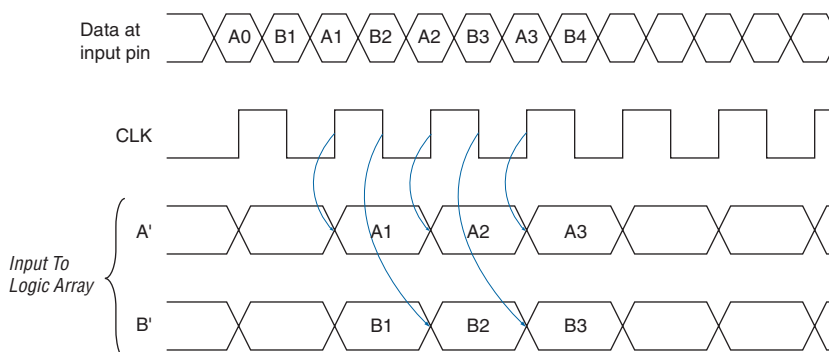
The IOE registers in Stratix devices share the same source for clear or preset. You can program preset or clear for each individual IOE. You can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power-up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally a synchronous reset signal is available for the IOE registers.

Double-Data Rate I/O Pins

Stratix devices have six registers in the IOE, which support DDR interfacing by clocking data on both positive and negative clock edges. The IOEs in Stratix devices support DDR inputs, DDR outputs, and bidirectional DDR modes.

When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used within the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times. This allows both bits of data to be synchronous with the same clock edge (either rising or falling).

Figure 2–65 shows an IOE configured for DDR input. Figure 2–66 shows the DDR input timing diagram.

Figure 2–66. Input Timing Diagram in DDR Mode

When using the IOE for DDR outputs, the two output registers are configured to clock two data paths from LEs on rising clock edges. These output registers are multiplexed by the clock to drive the output pin at a $\times 2$ rate. One output register clocks the first bit out on the clock high time, while the other output register clocks the second bit out on the clock low time. [Figure 2–67](#) shows the IOE configured for DDR output. [Figure 2–68](#) shows the DDR output timing diagram.

Table 2–32 shows I/O standard support for each I/O bank.

Table 2–32. I/O Support by Bank (Part 1 of 2)			
I/O Standard	Top & Bottom Banks (3, 4, 7 & 8)	Left & Right Banks (1, 2, 5 & 6)	Enhanced PLL External Clock Output Banks (9, 10, 11 & 12)
LVTTTL	✓	✓	✓
LVC MOS	✓	✓	✓
2.5 V	✓	✓	✓
1.8 V	✓	✓	✓
1.5 V	✓	✓	✓
3.3-V PCI	✓		✓
3.3-V PCI-X 1.0	✓		✓
LVPECL		✓	✓
3.3-V PCML		✓	✓
LVDS		✓	✓
HyperTransport technology		✓	✓
Differential HSTL (clock inputs)	✓	✓	
Differential HSTL (clock outputs)			✓
Differential SSTL (clock outputs)			✓
3.3-V GTL	✓		✓
3.3-V GTL+	✓	✓	✓
1.5-V HSTL Class I	✓	✓	✓
1.5-V HSTL Class II	✓		✓
1.8-V HSTL Class I	✓	✓	✓
1.8-V HSTL Class II	✓		✓
SSTL-18 Class I	✓	✓	✓
SSTL-18 Class II	✓		✓
SSTL-2 Class I	✓	✓	✓
SSTL-2 Class II	✓	✓	✓
SSTL-3 Class I	✓	✓	✓

The output levels are compatible with systems of the same voltage as the power supply (i.e., when V_{CCIO} pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When V_{CCIO} pins are connected to a 3.3-V power supply, the output high is 3.3 V and is compatible with 3.3-V or 5.0-V systems.

Table 2–36 summarizes Stratix MultiVolt I/O support.

Table 2–36. Stratix MultiVolt I/O Support <i>Note (1)</i>										
V_{CCIO} (V)	Input Signal (5)					Output Signal (6)				
	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	✓	✓	✓ (2)	✓ (2)		✓				
1.8	✓ (2)	✓	✓ (2)	✓ (2)		✓ (3)	✓			
2.5			✓	✓		✓ (3)	✓ (3)	✓		
3.3			✓ (2)	✓	✓ (4)	✓ (3)	✓ (3)	✓ (3)	✓	✓

Notes to Table 2–36:

- (1) To drive inputs higher than V_{CCIO} but less than 4.1 V, disable the PCI clamping diode. However, to drive 5.0-V inputs to the device, enable the PCI clamping diode to prevent V_I from rising above 4.0 V.
- (2) The input pin current may be slightly higher than the typical value.
- (3) Although V_{CCIO} specifies the voltage necessary for the Stratix device to drive out, a receiving device powered at a different level can still interface with the Stratix device if it has inputs that tolerate the V_{CCIO} value.
- (4) Stratix devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (5) This is the external signal that is driving the Stratix device.
- (6) This represents the system voltage that Stratix supports when a V_{CCIO} pin is connected to a specific voltage level. For example, when V_{CCIO} is 3.3 V and if the I/O standard is LVTTTL/LVCMOS, the output high of the signal coming out from Stratix is 3.3 V and is compatible with 3.3-V or 5.0-V systems.

High-Speed Differential I/O Support

Stratix devices contain dedicated circuitry for supporting differential standards at speeds up to 840 Mbps. The following differential I/O standards are supported in the Stratix device: LVDS, LVPECL, HyperTransport, and 3.3-V PCML.

There are four dedicated high-speed PLLs in the EP1S10 to EP1S25 devices and eight dedicated high-speed PLLs in the EP1S30 to EP1S80 devices to multiply reference clocks and drive high-speed differential SERDES channels.



See the Stratix device pin-outs at www.altera.com for additional high speed DIFFIO pin information for Stratix devices.

Table 2–39. EP1S40 Differential Channels (Part 2 of 2) Note (1)

Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs				Corner Fast PLLs (2), (3)			
				PLL1	PLL2	PLL3	PLL4	PLL7	PLL8	PLL9	PLL10
956-pin BGA	Transmitter (4)	80	840	18	17	17	18	20	20	20	20
			840 (5)	35	35	35	35	20	20	20	20
	Receiver	80	840	20	20	20	20	18	17	17	18
			840 (5)	40	40	40	40	18	17	17	18
1,020-pin FineLine BGA	Transmitter (4)	80 (10) (7)	840	18 (2)	17 (3)	17 (3)	18 (2)	20	20	20	20
			840 (5), (8)	35 (5)	35 (5)	35 (5)	35 (5)	20	20	20	20
	Receiver	80 (10) (7)	840	20	20	20	20	18 (2)	17 (3)	17 (3)	18 (2)
			840 (5), (8)	40	40	40	40	18 (2)	17 (3)	17 (3)	18 (2)
1,508-pin FineLine BGA	Transmitter (4)	80 (10) (7)	840	18 (2)	17 (3)	17 (3)	18 (2)	20	20	20	20
			840 (5), (8)	35 (5)	35 (5)	35 (5)	35 (5)	20	20	20	20
	Receiver	80 (10) (7)	840	20	20	20	20	18 (2)	17 (3)	17 (3)	18 (2)
			840 (5), (8)	40	40	40	40	18 (2)	17 (3)	17 (3)	18 (2)

Table 2–40. EP1S60 Differential Channels (Part 1 of 2) Note (1)

Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs				Corner Fast PLLs (2), (3)			
				PLL1	PLL2	PLL3	PLL4	PLL7	PLL8	PLL9	PLL10
956-pin BGA	Transmitter (4)	80	840	12	10	10	12	20	20	20	20
			840 (5), (8)	22	22	22	22	20	20	20	20
	Receiver	80	840	20	20	20	20	12	10	10	12
			840 (5), (8)	40	40	40	40	12	10	10	12

The transmitter external clock output is transmitted on a data channel. The `txclk` pin for each bank is located in between data transmitter pins. For $\times 1$ clocks (e.g., 622 Mbps, 622 MHz), the high-speed PLL clock bypasses the SERDES to drive the output pins. For half-rate clocks (e.g., 622 Mbps, 311 MHz) or any other even-numbered factor such as $1/4$, $1/7$, $1/8$, or $1/10$, the SERDES automatically generates the clock in the Quartus II software.

For systems that require more than four or eight high-speed differential I/O clock domains, a SERDES bypass implementation is possible using IOEs.

Byte Alignment

For high-speed source synchronous interfaces such as POS-PHY 4, XSBI, RapidIO, and HyperTransport technology, the source synchronous clock rate is not a byte- or SERDES-rate multiple of the data rate. Byte alignment is necessary for these protocols since the source synchronous clock does not provide a byte or word boundary since the clock is one half the data rate, not one eighth. The Stratix device's high-speed differential I/O circuitry provides dedicated data realignment circuitry for user-controlled byte boundary shifting. This simplifies designs while saving LE resources. An input signal to each fast PLL can stall deserializer parallel data outputs by one bit period. You can use an LE-based state machine to signal the shift of receiver byte boundaries until a specified pattern is detected to indicate byte alignment.

Power Sequencing & Hot Socketing

Because Stratix devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the `VCCIO` and `VCCINT` power supplies may be powered in any order.

Although you can power up or down the `VCCIO` and `VCCINT` power supplies in any sequence, you should not power down any I/O banks that contain configuration pins while leaving other I/O banks powered on. For power up and power down, all supplies (`VCCINT` and all `VCCIO` power planes) must be powered up and down within 100 ms of each other. This prevents I/O pins from driving out.

Signals can be driven into Stratix devices before and during power up without damaging the device. In addition, Stratix devices do not drive out during power up. Once operating conditions are reached and the device is configured, Stratix devices operate as specified by the user. For more information, see *Hot Socketing* in the *Selectable I/O Standards in Stratix & Stratix GX Devices* chapter in the *Stratix Device Handbook, Volume 2*.

configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. The I/O pins are tri-stated during power-up, and before and during configuration. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Stratix devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. You can perform in-field upgrades by distributing new configuration files either within the system or remotely.

PORSEL is a dedicated input pin used to select POR delay times of 2 ms or 100 ms during power-up. When the PORSEL pin is connected to ground, the POR time is 100 ms; when the PORSEL pin is connected to V_{CC} , the POR time is 2 ms.

The nIO_PULLUP pin enables a built-in weak pull-up resistor to pull all user I/O pins to V_{CCIO} before and during device configuration. If nIO_PULLUP is connected to V_{CC} during configuration, the weak pull-ups on all user I/O pins are disabled. If connected to ground, the pull-ups are enabled during configuration. The nIO_PULLUP pin can be pulled to 1.5, 1.8, 2.5, or 3.3 V for a logic level high.

VCCSEL is a dedicated input that is used to choose whether all dedicated configuration and JTAG input pins can accept 1.5 V/1.8 V or 2.5 V/3.3 V during configuration. A logic low sets 3.3 V/2.5 V, and a logic high sets 1.8 V/1.5 V. VCCSEL affects the following pins: TDI, TMS, TCK, TRST, MSEL0, MSEL1, MSEL2, $nCONFIG$, nCE , DCLK, PLL_ENA , $CONF_DONE$, $nSTATUS$. The VCCSEL pin can be pulled to 1.5, 1.8, 2.5, or 3.3 V for a logic level high.

The VCCSEL signal does not control the dual-purpose configuration pins such as the $DATA[7..0]$ and PPA pins (nWS , nRS , CS , nCS , and $RDYnBSY$). During configuration, these dual-purpose pins will drive out voltage levels corresponding to the V_{CCIO} supply voltage that powers the I/O bank containing the pin. After configuration, the dual-purpose pins use I/O standards specified in the user design.

TDO and $nCEO$ drive out at the same voltages as the V_{CCIO} supply that powers the I/O bank containing the pin. Users must select the V_{CCIO} supply for bank containing TDO accordingly. For example, when using the ByteBlaster™ MV cable, the V_{CCIO} for the bank containing TDO must be powered up at 3.3 V.

Table 4–10. 3.3-V LVDS I/O Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{ICM}	Input common mode voltage (6)	LVDS $0.3\text{ V} \leq V_{ID} \leq 1.0\text{ V}$ $W = 1$ through 10	100		1,100	mV
		LVDS $0.3\text{ V} \leq V_{ID} \leq 1.0\text{ V}$ $W = 1$ through 10	1,600		1,800	mV
		LVDS $0.2\text{ V} \leq V_{ID} \leq 1.0\text{ V}$ $W = 1$	1,100		1,600	mV
		LVDS $0.1\text{ V} \leq V_{ID} \leq 1.0\text{ V}$ $W = 2$ through 10	1,100		1,600	mV
V_{OD} (7)	Output differential voltage (single-ended)	$R_L = 100\ \Omega$	250	375	550	mV
ΔV_{OD}	Change in V_{OD} between high and low	$R_L = 100\ \Omega$			50	mV
V_{OCM}	Output common mode voltage	$R_L = 100\ \Omega$	1,125	1,200	1,375	mV
ΔV_{OCM}	Change in V_{OCM} between high and low	$R_L = 100\ \Omega$			50	mV
R_L	Receiver differential input discrete resistor (external to Stratix devices)		90	100	110	Ω

Table 4–47. DSP Block Internal Timing Microparameters (Part 2 of 2)

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{PIPE2OUTREG2ADD}}$		2,002		2,203		2,533		2,980	ps
$t_{\text{PIPE2OUTREG4ADD}}$		2,899		3,189		3,667		4,314	ps
t_{PD9}		3,709		4,081		4,692		5,520	ps
t_{PD18}		4,795		5,275		6,065		7,135	ps
t_{PD36}		7,495		8,245		9,481		11,154	ps
t_{CLR}	450		500		575		676		ps
t_{CLKHL}	1,350		1,500		1,724		2,029		ps

Table 4–48. M512 Block Internal Timing Microparameters

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{M512RC}		3,340		3,816		4,387		5,162	ps
t_{M512WC}		3,138		3,590		4,128		4,860	ps
$t_{\text{M512WERESU}}$	110		123		141		166		ps
$t_{\text{M512WEREH}}$	34		38		43		51		ps
$t_{\text{M512CLKENSU}}$	215		215		247		290		ps
$t_{\text{M512CLKENH}}$	–70		–70		–81		–95		ps
$t_{\text{M512DATASU}}$	110		123		141		166		ps
$t_{\text{M512DATAH}}$	34		38		43		51		ps
$t_{\text{M512WADDRSU}}$	110		123		141		166		ps
$t_{\text{M512WADDRH}}$	34		38		43		51		ps
$t_{\text{M512RADDRSU}}$	110		123		141		166		ps
$t_{\text{M512RADDRH}}$	34		38		43		51		ps
$t_{\text{M512DATACO1}}$		424		472		541		637	ps
$t_{\text{M512DATACO2}}$		3,366		3,846		4,421		5,203	ps
$t_{\text{M512CLKHL}}$	1,000		1,111		1,190		1,400		ps
t_{M512CLR}	170		189		217		255		ps

Table 4–53. Stratix Regional Clock External I/O Timing Parameters (Part 2 of 2) Notes (1), (2)

Symbol	Parameter
t_{XZPLL}	Synchronous IOE output enable register to output pin disable delay using regional clock fed by Enhanced PLL with default phase setting
t_{ZXPLL}	Synchronous IOE output enable register to output pin enable delay using regional clock fed by Enhanced PLL with default phase setting

Notes to Table 4–53:

- (1) These timing parameters are sample-tested only.
- (2) These timing parameters are for column and row IOE pins. You should use the Quartus II software to verify the external timing for any pin.

Table 4–54 shows the external I/O timing parameters when using global clock networks.

Table 4–54. Stratix Global Clock External I/O Timing Parameters Notes (1), (2)

Symbol	Parameter
t_{INSU}	Setup time for input or bidirectional pin using IOE input register with global clock fed by CLK pin
t_{INH}	Hold time for input or bidirectional pin using IOE input register with global clock fed by CLK pin
t_{OUTCO}	Clock-to-output delay output or bidirectional pin using IOE output register with global clock fed by CLK pin
$t_{INSUPLL}$	Setup time for input or bidirectional pin using IOE input register with global clock fed by Enhanced PLL with default phase setting
t_{INHPLL}	Hold time for input or bidirectional pin using IOE input register with global clock fed by Enhanced PLL with default phase setting
$t_{OUTCOPLL}$	Clock-to-output delay output or bidirectional pin using IOE output register with global clock Enhanced PLL with default phase setting
t_{XZPLL}	Synchronous IOE output enable register to output pin disable delay using global clock fed by Enhanced PLL with default phase setting
t_{ZXPLL}	Synchronous IOE output enable register to output pin enable delay using global clock fed by Enhanced PLL with default phase setting

Notes to Table 4–54:

- (1) These timing parameters are sample-tested only.
- (2) These timing parameters are for column and row IOE pins. You should use the Quartus II software to verify the external timing for any pin.

Table 4–105. Stratix I/O Standard Output Delay Adders for Fast Slew Rate on Column Pins (Part 2 of 2)

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
CTT		973		1,021		1,021		1,021	ps
SSTL-3 Class I		719		755		755		755	ps
SSTL-3 Class II		146		153		153		153	ps
SSTL-2 Class I		678		712		712		712	ps
SSTL-2 Class II		223		234		234		234	ps
SSTL-18 Class I		1,032		1,083		1,083		1,083	ps
SSTL-18 Class II		447		469		469		469	ps
1.5-V HSTL Class I		660		693		693		693	ps
1.5-V HSTL Class II		537		564		564		564	ps
1.8-V HSTL Class I		304		319		319		319	ps
1.8-V HSTL Class II		231		242		242		242	ps

Table 4–106. Stratix I/O Standard Output Delay Adders for Fast Slew Rate on Row Pins (Part 1 of 2)

Parameter		-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA		1,518		1,594		1,594		1,594	ps
	4 mA		746		783		783		783	ps
	8 mA		96		100		100		100	ps
	12 mA		0		0		0		0	ps
3.3-V LVTTTL	4 mA		1,518		1,594		1,594		1,594	ps
	8 mA		1,038		1,090		1,090		1,090	ps
	12 mA		521		547		547		547	ps
	16 mA		414		434		434		434	ps
	24 mA		0		0		0		0	ps
2.5-V LVTTTL	2 mA		2,032		2,133		2,133		2,133	ps
	8 mA		699		734		734		734	ps
	12 mA		374		392		392		392	ps
	16 mA		165		173		173		173	ps
1.8-V LVTTTL	2 mA		3,714		3,899		3,899		3,899	ps
	8 mA		1,055		1,107		1,107		1,107	ps
	12 mA		830		871		871		871	ps

The scaling factors for column output pin timing in Tables 4–111 to 4–113 are shown in units of time per pF unit of capacitance (ps/pF). Add this delay to the t_{CO} or combinatorial timing path for output or bidirectional pins in addition to the I/O adder delays shown in Tables 4–103 through 4–108 and the IOE programmable delays in Tables 4–109 and 4–110.

Table 4–111. Output Delay Adder for Loading on LVTTTL/LVCMOS Output Buffers *Note (1)*

Conditions		Output Pin Adder Delay (ps/pF)				
Parameter	Value	3.3-V LVTTTL	2.5-V LVTTTL	1.8-V LVTTTL	1.5-V LVTTTL	LVCMOS
Drive Strength	24mA	15	–	–	–	8
	16mA	25	18	–	–	–
	12mA	30	25	25	–	15
	8mA	50	35	40	35	20
	4mA	60	–	–	80	30
	2mA	–	75	120	160	60

Note to Table 4–111:

- (1) The timing information in this table is preliminary.

Table 4–112. Output Delay Adder for Loading on SSTL/HSTL Output Buffers *Note (1)*

Conditions		Output Pin Adder Delay (ps/pF)			
		SSTL-3	SSTL-2	SSTL-1.8	1.5-V HSTL
Class I		25	25	25	25
Class II		25	20	25	20

Note to Table 4–112:

- (1) The timing information in this table is preliminary.

Table 4–113. Output Delay Adder for Loading on GTL+/GTL/CTT/PCI Output Buffers *Note (1)*

Conditions		Output Pin Adder Delay (ps/pF)				
Parameter	Value	GTL+	GTL	CTT	PCI	AGP
VCCIO Voltage Level	3.3V	18	18	25	20	20
	2.5V	15	18	–	–	–

Note to Table 4–113:

- (1) The timing information in this table is preliminary.

PLL Specifications

Tables 4–127 through 4–129 describe the Stratix device enhanced PLL specifications.

Table 4–127. Enhanced PLL Specifications for -5 Speed Grades (Part 1 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	3 (1), (2)		684	MHz
f_{INPFD}	Input frequency to PFD	3		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$f_{EINDUTY}$	External feedback clock input duty cycle	40		60	%
$t_{INJITTER}$	Input clock period jitter			±200 (3)	ps
$t_{EINJITTER}$	External feedback clock period jitter			±200 (3)	ps
t_{FCOMP}	External feedback clock compensation time (4)			6	ns
f_{OUT}	Output frequency for internal global or regional clock	0.3		500	MHz
f_{OUT_EXT}	Output frequency for external clock (3)	0.3		526	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45		55	%
t_{JITTER}	Period jitter for external clock output (6)			±100 ps for >200-MHz outclk ±20 mUI for <200-MHz outclk	ps or mUI
$t_{CONFIG5,6}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{SCANCLK}$	
$t_{CONFIG11,12}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{SCANCLK}$	
$t_{SCANCLK}$	scanclk frequency (5)			22	MHz
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7)			100	μs
t_{LOCK}	Time required to lock from end of device configuration	10		400	μs
f_{VCO}	PLL internal VCO operating range	300		800 (8)	MHz
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		±50		ps

Differential HSTL Specifications 4-15

DSP

Block Diagram

Configuration

for 18 x 18-Bit 2-55

for 9 x 9-Bit 2-56

Block Interconnect Interface 2-71

Block Interface 2-70

Block Signal Sources & Destinations 2-73

Blocks

Arranged in Columns 2-53

in Stratix Devices 2-54

Input Register Modes 2-60

Input Registers 2-58

Multiplier

2-60

Block 2-57

Signed Representation 2-60

Sub-Block 2-57

Sub-Blocks Using Input Shift Register

Connections 2-59

Pipeline/Post Multiply Register 2-61

E

EP1S10 Devices

Column Pin

Fast Regional Clock External I/O Timing
Parameters 4-36

Global Clock External I/O Timing
Parameters 4-37

Regional Clock External I/O Timing
Parameters 4-36

Row Pin

Fast Regional Clock External I/O Timing
Parameters 4-37

Global Clock External I/O Timing
Parameters 4-38

Regional Clock External I/O Timing
Parameters 4-38

EP1S20 Devices

Column Pin

Fast Regional Clock External I/O Timing
Parameters 4-39

Global Clock External I/O Timing
Parameters 4-40

Regional Clock External I/O Timing

Parameters 4-39

Row Pin

Fast Regional Clock External I/O Timing
Parameters 4-40

Global Clock External I/O Timing
Parameters 4-41

Regional Clock External I/O Timing
Parameters 4-41

EP1S25 Devices

Column Pin

Fast Regional Clock External I/O Timing
Parameters 4-42

Global Clock External I/O Timing
Parameters 4-43

Regional Clock External I/O Timing
Parameters 4-42

Row Pin

Fast Regional Clock External I/O Timing
Parameters 4-43

Global Clock External I/O Timing
Parameters 4-44

Regional Clock External I/O Timing
Parameters 4-44

EP1S30 Devices

Column Pin

Fast Regional Clock External I/O Timing
Parameters 4-45

Global Clock External I/O Timing
Parameters 4-45

Regional Clock External I/O Timing
Parameters 4-45

Row Pin

Fast Regional Clock External I/O Timing
Parameters 4-46

Global Clock External I/O Timing
Parameters 4-47

Regional Clock External I/O Timing
Parameters 4-47

EP1S40 Devices

Column Pin

Fast Regional Clock External I/O Timing
Parameters 4-48

Global Clock External I/O Timing
Parameters 4-49

Regional Clock External I/O Timing
Parameters 4-48

Row Pin